



PATENT
455610-2590.3

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

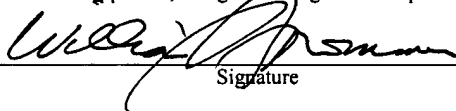
Applicants : Martin MILLER et al.
Serial No. : 10/673,713
Filing Date : September 29, 2003
For : METHOD AND APPARATUS FOR ANALYZING SERIAL
DATA STREAMS
Examiner : To Be Assigned
Art Unit : 2186

745 Fifth Avenue
New York, NY 10151

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Mail Stop Missing Parts Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on December 3, 2004.

Gordon Kessler, Reg. No. 38,511

Name of Applicant, Assignee or Registered Representative



Signature

December 3, 2004

Date of Signature

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir

In compliance with the duty of disclosure set forth in 37 C.F.R. 1.56, Applicants are filing this Information Disclosure Statement, the accompanying form PTO-1449 and the documents noted thereon.

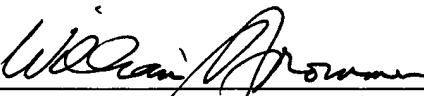
So far as Applicants are aware, this Information Disclosure Statement is being filed before the mailing date of the first Office Action on the merits.

The filing of this Information Disclosure Statement is not an admission that the documents identified herein constitute prior art to the present application.

It is believed that no fees are required by the instant submission as it is prior to receipt of the first Office Action in this application. However, if any fees are required, or if any overpayment has been made, please charge Deposit Acct. No. 50-0320.

Respectfully submitted,

FROMMER LAWRENCE & HAUG LLP
Attorney for Applicants

By: 
William S. Frommer
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Encs. - PTO Form 1449

Based on Form PTO-1449
(3/90)

ATTY. DOCKET NO.

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SERIAL NO.

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LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT

Martin MILLER et al.

FILING DATE

September 29, 2003

GROUP

2186

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	5,654,987	08/05/97	Nakamura			
	AB	5,726,607	03/10/98	Brede et al			
	AC	5,825,825	10/20/98	Altmann et al			
	AD	5,900,755	05/04/99	Toeppen et al			
	AE	6,215,363	04/10/01	Conta et al			
	AF	6,295,327	09/25/01	Takla			
	AG	6,445,230	09/03/02	Rupp et al			
	AH	4,680,778	07/14/87	Krinoock			
	AI	5,943,378	08/24/99	Keba et al			
	AJ	6,188,737	02/13/01	Bruce et al			
	AK	5,914,592	06/22/99	Saito			
	AL	5,789,954	08/04/98	Toeppen et al			
	AM	4,694,244	08/15/87	Whiteside et al			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AN	JP4105070	04/07/92	Japan			Abstract	
	AO	JP5196641	08/06/93	Japan			Abstract	
	AP	JP5264595	10/12/93	Japan			Abstract	
	AQ	JP8220144	06/22/99	Japan			Abstract	
	AR	JP9005362	01/10/97	Japan			Abstract	
	AS	JP10163859	06/19/98	Japan			Abstract	
	AT	JP11098876	04/09/99	Japan			Abstract	
	AU	JP62003544	01/09/87	Japan			Abstract	
	AV	EP 0 631 143	12/28/94	Europe				
	AW	EP 0 241 142	10/14/87	Europe				

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AY		Roland E. Best, <i>The Software PLL, Phase Locked Loops</i> , 3 rd Edition, McGraw-Hill, New York, 1997, pp 229-249
	AZ		<i>Using FPGAs for Digital Applications</i> , Actel Corporation, April 1996
	BA		HP E4543A Q Factor and Eye Contours Application Software, Hewlett Packard, 1999
	BB		Infinium DCA, Agilent Technologies, March 7, 2002
	BC		Communication waveform measurements, Hewlett Packard, June 26, 1996

EXAMINER

DATE CONSIDERED

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	BD	4,633,465	12/30/86	Fitch et al.			
	BE	5,337,403	08/09/94	Klingman			
	BF						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	BG						Abstract	
	BH						Abstract	
	BI							

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	BJ		Advanced Analysis of High-Speed Digital Communication Waveforms, Hewlett Packard, June 27, 1994					
	BK		R.E. Anderson and E. M. Foster, Design of an MPEG-2 Transport Demultiplexor Core, IBM, 1999					
	BL		Technology Standards, Tektronix Website (www.tek.com/M Measurement/Solutions/tech_standards/index.html?wt=257)					
	BM		Communications Signal Analyzer, Tektronix Website (www.tektronix.com/optical)					
	BN		RT-Eye™ Serial Data Compliance and Analysis Software, Tektronix Website (www.Tektronix.com/accessories)					
	BO		Design of FIR Filters by Windowing, MIT Website, (http://web.mit.edu/6.555/www/fir.html)					
	BP		A New Digital PLL at the Technische Universitaet Berlin, Technische Universitaet Berlin Website (www.tdl.com/gottsch/tuberlin.htm)					
	BQ		Low Jitter Digital PLL – ZL30407, Zalink Semiconductor Website, (http://products.zarlink.com/product_portlets/new_timer.htm)					
	BR		Michael K. Williams, et al., A Discussion of Methods for Measuring Low-Amplitude Jitter, International Test Conference, Paper 28.1, pp 646-652					
	BS		Russ Brown, Quantam Corporation, "Eye Diagram Data", SCSI Physical Working Group, February 9, 2000					
	BT		Dave Fink, Tektronix "Introduction to Measurement Techniques and Analysis of Emerging Serial Data Standards", November 2002					
	BU		"Methodologies for Jitter Specification Technical Report" Rev 10, June 9, 1999					
	BV		Andy Baldman, University of New Hampshire "Description of XAUI Physical Layer Measurements Performed At The UNH Interoperability Lab", October 30, 2002					
	BW		University of New Hampshire Technical Document, "fast Ethernet" February 13, 2003					

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DATE CONSIDERED

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